Application/Control No.	lo. Applicant(s)/Patent under Reexamination	
10/811,207	YUE ET AL.	
Examiner	Art Unit	
Monica Lewis	2822	

SEARCHED					
Class	Subclass	Date	Examiner		
257	127,170, 339,409, 372-376	7/19/2007	ML		
257	394-400	7/19/2007	ML		
257	452,484	7/19/2007	ML		
257	490,605	7/19/2007	ML		
257	500-510	7/19/2007	ML		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOT (INCLUDING SEARCH	ES STRATEGY)	
	DATE	EXMR
EIC Search	7/19/2007	ML
East Search	7/19/2007	ML